

**Notice of References Cited**

Application/Control No.

10/603,049

Applicant(s)/Patent Under  
Reexamination  
VANN ET AL.

Examiner

Brian R. Gordon

Art Unit

1743

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0215956	11-2003	Reed, Mark T.	436/174
*	B	US-2002/0110900	08-2002	Jovanovich et al.	435/286.4
*	C	US-2004/0087033	05-2004	Schembri, Carol T.	436/180
*	D	US-6,783,732	08-2004	Madden et al.	422/63
*	E	US-6,682,702	01-2004	Barth et al.	422/102
*	F	US-6,569,385	05-2003	Little et al.	422/100
*	G	US-6,451,261	09-2002	Bodner et al.	422/99
*	H	US-6,423,536	07-2002	Jovanovich et al.	435/287.2
*	I	US-6,277,334	08-2001	Ecker et al.	422/131
*	J	US-6,136,274	10-2000	Nova et al.	422/102
*	K	US-5,925,732	07-1999	Ecker et al.	530/334
*	L	US-6,602,714	08-2003	Tagge et al.	436/2
*	M	US-6,037,124	03-2000	Matson, Robert S.	435/6

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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